

## Current Inventory

### Product Information

**KLA-Tencor P20H Long Scan  
Profiler**

choose one...



Measurement of vertical features  
ranging from 100A to 0.3mm  
Vertical resolution 1 to 25A  
Ability to fit and level data, allowing  
accurate measurements on curved  
surfaces  
Handles wafers from 3" to 8" cassette  
to cassette  
2-D and 3-D plots and contour maps  
Scan up to 25 wafers without  
operator intervention  
Full 8" scanning

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**ASM Ex. 1020**  
IPR Petition - USP 7,808,396